MEASURING OF ROUGHNESS AND SCATTERING PROPERTIES OF **OPTICAL SURFACES**

CASI SCHMITT INDUSTRIES, INC.

The CASI (Complete Angle Scatter Instrument) Scatterometer uses laser light as a nondestructive probe to measure surfaced quality, optical performance, smoothness, appearance, defects, and contamination on a wide variety of materials.We offer contract measuring on top-class light scatter instrument and roughness measuring instrument CASI from SCHMITT Industries, Inc..

ACQUIRED INFORMATION

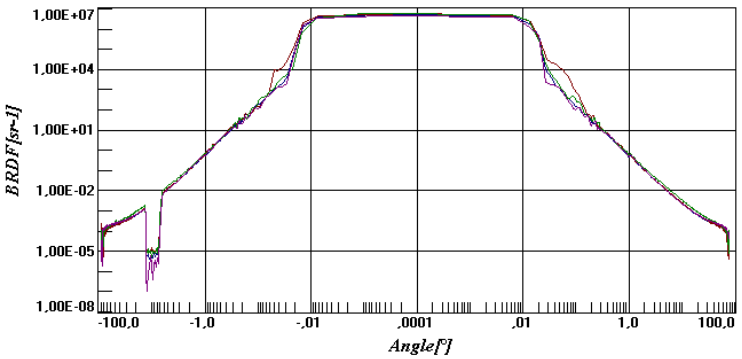
- Optical surface roughness
- Material pollution
- Surface defects and regular structures
- Complete scattered radiation field from materials

SAMPLE TYPES

- Accurately machined optical surfaces
- All diffuse materials
- Semiconductor wafers
- Mechanical components

MODES, CONDITIONS AND PRECISION

- The smallest measurable root mean square roughness value RMS (Rq) of the surface roughness is <1 nm
- Instrument measures all important parameters of the scattered radiation on wavelengths 325 nm a 633 nm
- Scattered light field from the material is being measured in transitivity field, as well as in reflected field in the interval -90° – 90° from the surface normal



Measured field of scattered radiation (function BRDF) from fine polished optical surface.

DETAILED INFORMATION ON REQUEST

REGIONAL CENTRE
OF ADVANCED TECHNOLOGIES
AND MATERIALS

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